

Introduction

Infineon technologies Austria is one of the leading semiconductor companies worldwide. With around 4,820 employees

Introduction to failure analysis

Failure Analysis process?

Detection and localization of faults in semiconductors is a knowledge-intensive and tedious task. To increase the chances of success, Modern Natural Language Processing methods (NLP) already showed their efficiency in various applications, including chatbots. This is why one of the first applications of Artificial Intelligence (AI) tools at the FA laboratory of Infineon consisted on

goal of the project

Problem Definition The goal of this project is to develop a FA report classifier with a BERT model. In order to do so, the task has been defined. First, we have developed a Language Model based on the state-of-the-art model BERT. Therefore we had to consider our data. Second, we focused on defining the structure of the classifier, which consisted on the BERT network and additional classification layers. Given the nature of this project the two phases were developed in parallel so the joint performance hasn't been tested yet.

Research Questions This thesis will address the following research questions:

What kind of BERT models already exist

How well do they fit to the Infineon semiconductor domain

What data to use for further training

Evaluation of the resulting model

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general structure of the project

In order to fulfill this goal, an innovative language model trained on the semiconductor domain had to be developed.

Structure of the thesis

The following chapters